

MODEL SELECTION

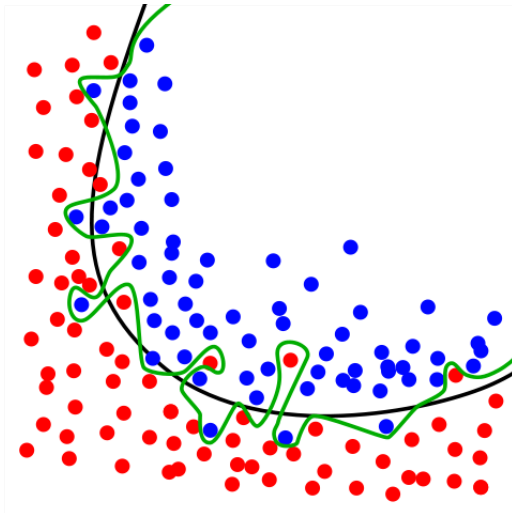
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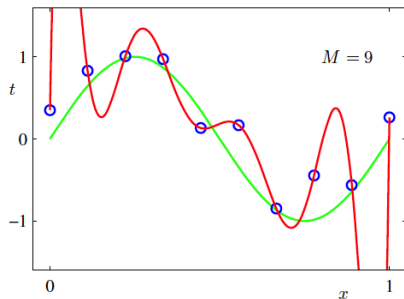
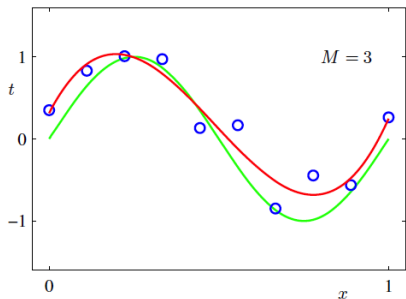
- 1 OVERFITTING. BIAS-VARIANCE DECOMPOSITION
- 2 MODEL QUALITY CRITERIA
- 3 LINEAR REGRESSION MODEL SELECTION
- 4 REGULARIZATION
- 5 FEATURE SELECTION

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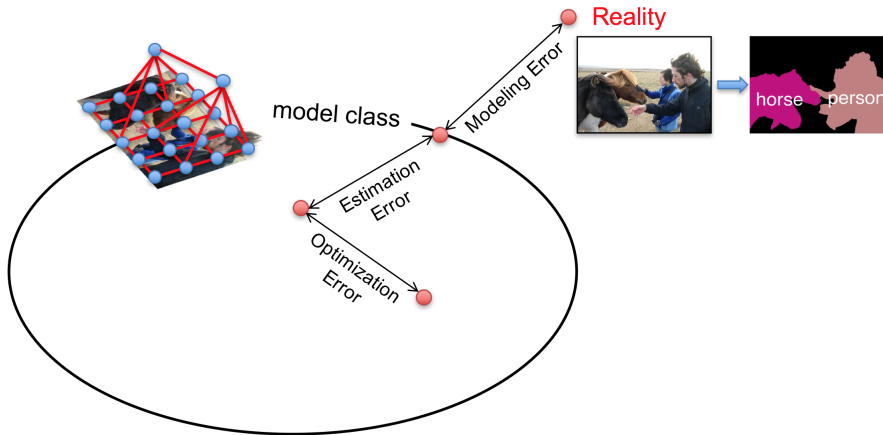
OVERFITTING: KNN



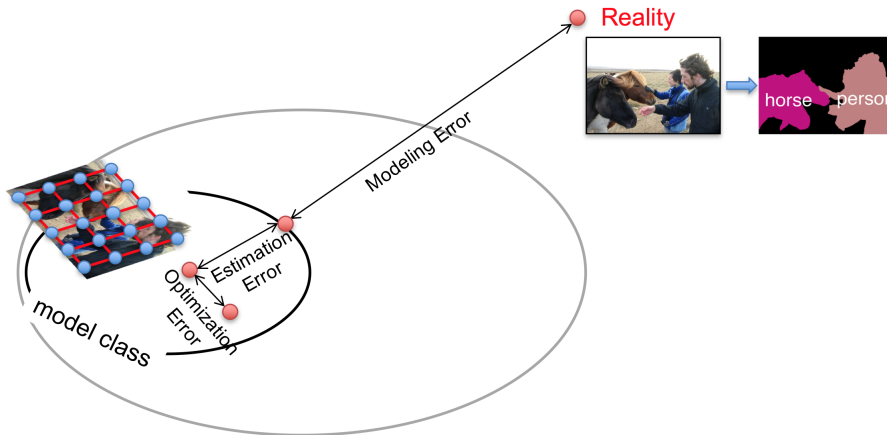
OVERFITTING: REGRESSION



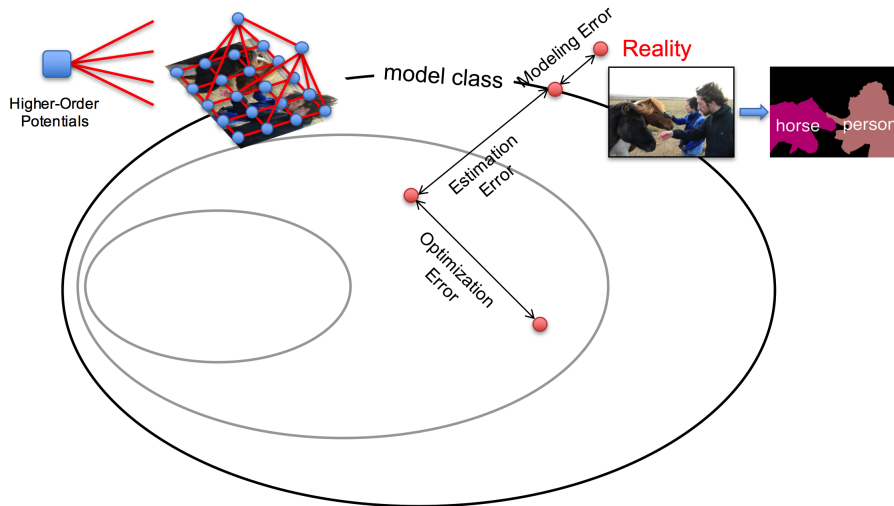
ERROR DECOMPOSITION I



ERROR DECOMPOSITION II



ERROR DECOMPOSITION III



ERROR DECOMPOSITION IV

- Approximation/Modeling Error
 - You approximated reality with a model
- Estimation Error
 - You tried to learn model with finite data
- Optimization Error
 - You were lazy and couldn't/didn't optimize to completion
- Bayes Error
 - Reality just sucks (i.e. there is a lower bound on error for all models, usually non-zero)

THE BIAS-VARIANCE DECOMPOSITION

- Using regression as model, assume that

$$y = f(\mathbf{x}) + \varepsilon,$$

where $\mathbb{E}\varepsilon = 0$, $\text{Var}(\varepsilon) = \sigma_\varepsilon^2$

- Then at an input point $\mathbf{x} = \mathbf{x}_0$

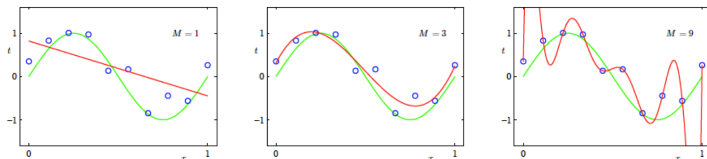
$$\begin{aligned} \text{Err}(\mathbf{x}_0) &= \mathbb{E} \left[(y - \hat{f}(\mathbf{x}_0))^2 | \mathbf{x} = \mathbf{x}_0 \right] \\ &= \sigma_\varepsilon^2 + \left[\mathbb{E} \hat{f}(\mathbf{x}_0) - f(\mathbf{x}_0) \right]^2 + \mathbb{E} \left[\hat{f}(\mathbf{x}_0) - \mathbb{E} \hat{f}(\mathbf{x}_0) \right]^2 \\ &= \sigma_\varepsilon^2 + \text{Bias}^2 \left(\hat{f}(\mathbf{x}_0) \right) + \mathbb{V} \left(\hat{f}(\mathbf{x}_0) \right) \\ &= \text{Irreducible Error} + \text{Bias}^2 + \text{Variance} \end{aligned}$$

BIAS-VARIANCE TRADEOFF

- **Bias:** difference between what you expect to learn and the truth
 - Measures how well you expect to represent true solution
 - Decreases with more complex model
- **Variance:** difference between what you expect to learn and what you learn from a particular dataset
 - Measures how sensitive learner is to specific dataset
 - Increases with more complex model

LINEAR REGRESSION

- Example: polynomial regression $h(x) = \sum_{m=0}^M w_m x^m$



- Value of the optimal (ML) regression coefficients

	$m = 0$	$m = 1$	$m = 3$	$m = 9$
w_0^*	0.19	0.82	0.31	0.35
w_1^*		-1.27	7.99	232.37
w_2^*			-25.43	-5321.83
w_3^*			17.37	48568.31
w_4^*				-231639.30
w_5^*				640042.26
w_6^*				-1061800.52
w_7^*				1042400.18
w_8^*				-557682.99
w_9^*				125201.43

K-NN REGRESSION EXAMPLE

- Assume average of k nearest neighbors

$$\begin{aligned} Err(\mathbf{x}_0) &= \mathbb{E} \left[(y - \hat{f}(\mathbf{x}_0))^2 | \mathbf{x} = \mathbf{x}_0 \right] \\ &= \sigma_\varepsilon^2 + \left[f(\mathbf{x}_0) - \frac{1}{k} \sum_{\mathbf{x} \in k\text{NN}(\mathbf{x}_0)} f(\mathbf{x}) \right]^2 + \frac{\sigma_\varepsilon^2}{k} \end{aligned}$$

- For small k , good fit (small bias), larger variance. For big k , more bias, less variance
- This is a model selection problem

WHAT IS MODEL SELECTION?

- Given a set of models $\mathcal{H} = \{H_1, \dots, H_K\}$, choose the model **expected to do the best on the test data**
- \mathcal{H} may consist of
 1. Same learning model with different complexities of hyperparameters
 - Nonlinear regression: polynomials with different degrees
 - k -Nearest Neighbors: Different choices of k
 - Decision Trees: Different choices of the number of levels/leaves
 - SVM: Different choices of the misclassification penalty hyperparameter C
 - Regularized Models: Different choices of the regularization parameter
 - Kernel based Methods: Different choices of kernels, etc.
 2. Different learning models (e.g., SVM, KNN, DT, etc.)
- Note: Usually considered in supervised learning contexts but unsupervised learning also faces this issue (e.g., “how many clusters” when doing clustering)

MODEL SELECTION

- Occam's razor: among competing hypotheses, the one with the fewest assumptions should be selected
- Too much variables/parameters \Rightarrow significant prediction variance and small bias on the training sample, and vice versa
- We have two interrelated problems
 - to estimate value of a target function, characterizing generalization ability of the considered model
 - select an optimal model w.r.t. to the constructed accuracy criterion

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MODEL SELECTION PROBLEM STATEMENT

- Input:
 - Training sample $S_m = \{(\mathbf{x}_i, y_i)\}_{i=1}^m$, $\mathbf{x} \in X$, $y \in Y$
 - $H_n = \{h : X \rightarrow Y\}$ is a hypothesis set, $n = 1, 2, \dots$
 - $\mathcal{L}_n : (X \times Y)^m \rightarrow H_n$ is a learner, $n = 1, 2, \dots$
- Output: obtain a learner with the best generalization ability
- Examples:
 - Select the best model H_n (model selection)
 - Select the best learner \mathcal{L}_n for a given model H (e.g. hyperparameters tuning)
 - Select subset of features $\mathbf{x}_J = (x_j, j \in J)$ from the available features $\mathbf{x} = (x_1, \dots, x_N)$, i.e. the learner \mathcal{L} uses only features \mathbf{x}_J

EMPIRICAL ERROR

- $L(h(\mathbf{x}), y)$ is a loss for a pair (\mathbf{x}, y) and a model h
- $\hat{R}(h; S_m) = \frac{1}{m} \sum_{i=1}^m L(h(\mathbf{x}_i), y_i)$ is a loss of h on S_m
- Empirical Training Error

$$\hat{R}_{\mathcal{L}}(S_m) = \hat{R}(h; S_m), \quad h(\cdot) = \mathcal{L}(S_m)$$

This error is a biased estimate of the generalization risk

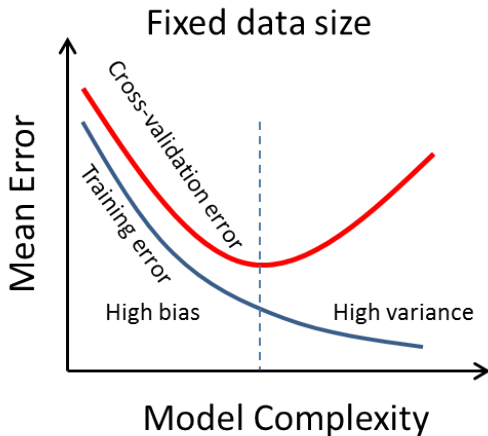
- Empirical Test Error is estimated using a hold-out test sample S^t

$$\hat{R}_{\mathcal{L}}(S_m; S^t) = \hat{R}(h; S^t), \quad h(\cdot) = \mathcal{L}(S_m)$$

- either we need an additional test set S^t
- or we have to divide S_m into a train and a validation sets (results depend on this division)

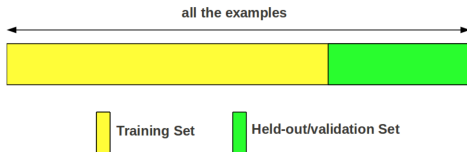
TRAIN VS. TEST ERROR

- Train Error decreases w.r.t. increasing model complexity
- Test Error increases w.r.t. increasing model complexity



HOLD-OUT DATA

- Set aside a fraction (say 10% – 20%) of the training data
- This part becomes our hold-out data (validation or development data)

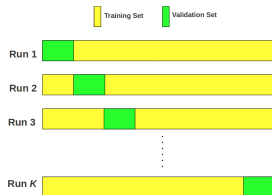


- Remember: hold-out data is NOT the test data
- Train each model using the remaining training data
- Evaluate error on the hold-out data
- Choose the model with the smallest hold-out error
- Problems:
 - Wastes training data, so typically used when we have plenty of training data
 - Hold-out data may not be good if there was an unfortunate split (use random splitting!)

CROSS-VALIDATION

K -fold Cross-Validation

- Create K equal sized partitions of the training data
- Each partition has m/K examples
- Train using $K - 1$ partitions, validate on the remaining partitions
- Repeat the same K times, each with a different validation partition



- Finally, choose the model with smallest average validation error
- Usually K is chosen as 10

CROSS-VALIDATION

$M \times K$ -fold Cross-Validation

- We divide the training sample M times into K equal sized partitions
- Results of all M K -fold cross-validations are aggregated (e.g. averaged)
- By increasing M we can improve accuracy
- Each object is used in a test set M times
- We can construct confidence intervals using results of M repetitions

BOOTSTRAPPING

- Given: a set of m examples
- Idea: Sample m elements from this set with replacement
 - An already sampled element could be picked again
- Use this new sample as the training data
- Use the set of examples not selected as the validation data
- For large m , training data consists of about only 63% unique examples
- Training data is inherently small \rightarrow error estimate may be pessimistic
- Use the following equation to compute the expected model error

$$\hat{R} = 0.632 \times R_{test} + 0.368 \times R_{train}$$

MODEL CONSISTENCY

- If a hypothesis set H is appropriate, then models $h = \mathcal{L}(S)$, constructed for different subsets $S \subset S_m$ should be “similar”
- E.g. we can divide S_m M -times into two parts $\{S_m^{1,i} \cup S_m^{2,i}\}$, $i = 1, 2, \dots, M$ and calculate

$$\Delta_M(H, \mathcal{L}; S_m) = \frac{1}{M} \sum_{i=1}^M \frac{1}{m} \sum_{j=1}^m |\mathcal{L}(S_m^{1,i})(\mathbf{x}_j) - \mathcal{L}(S_m^{2,i})(\mathbf{x}_j)|$$

- Problems:
 - Sample size is two times smaller
 - Computational complexity is two times bigger

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NOTATIONS

- Training sample $S_m = \{(\mathbf{x}_i, y_i)\}_{i=1}^m$, $\mathbf{x} \in X$, $y \in Y$
- $\mathbf{X} = \{\mathbf{x}_i, i = 1, \dots, m\}$ is a design matrix
- We consider a linear model $h(\mathbf{x}) = \mathbf{w}^T \cdot \mathbf{x} + b$, $\mathbf{w} \in \mathbb{R}^N$, $\mathbf{x} \in \mathbb{R}^N$ in a stochastic white noise setting
- Let $J \subseteq \{1, \dots, N\}$ be a subset of features from \mathbf{x} we use to construct a linear model
- We denote by
 - \mathbf{X}_J a submatrix of the full feature matrix \mathbf{X} , selected according to the specified subset of feature
 - \mathbf{w}_J linear model coefficients, corresponding to \mathbf{X}_J , $\hat{\mathbf{w}}_J$ are their estimates by the least squares method
 - $\hat{h}_J(\mathbf{x}) = \hat{\mathbf{w}}_J^T \cdot \mathbf{x}_J + \hat{b}$ a regression function,
 $\hat{y}_i(J) = \hat{h}_J(\mathbf{x}_i)$

REGRESSION RISK

- Risk of a prediction (in-sample error)

$$R(J) = \frac{1}{m} \sum_{i=1}^m \mathbb{E}(\hat{y}_i(J) - y_i^*)^2,$$

where y_i^* is a newly randomly generated y_i (with independently generated noise value) for the same \mathbf{x}_i

- The problem is to select J , such that $R(J)$ is small
- Risk estimate on the training set is equal to

$$\hat{R}_{\text{tr}}(J) = \frac{1}{m} \sum_{i=1}^m (\hat{y}_i(J) - y_i)^2$$

- **Theorem:** $\mathbb{E}(\hat{R}_{\text{tr}}(J)) < R(J)$ and

$$\text{bias}(\hat{R}_{\text{tr}}(J)) = \mathbb{E}(\hat{R}_{\text{tr}}(J)) - R(J) = -\frac{2}{m} \sum_{i=1}^m \text{Cov}(\hat{y}_i, y_i)$$

C_p MALLOW

- It can be proved, that in the linear case

$$2 \sum_{i=1}^m \text{Cov}(\hat{y}_i, y_i) \sim 2|J|\hat{\sigma}^2,$$

where $\hat{\sigma}^2$ is an estimate of an output noise standard deviation σ^2 , obtained using residuals on the training set, calculated by fitting the model

- Thus, we get C_p Mallow statistics, representing asymptotically unbiased estimate of the regression risk

$$\hat{R}(J) = \hat{R}_{\text{tr}}(J) + 2\frac{\hat{\sigma}^2}{m}|J|$$

The second term here penalizes complexity

AIC & BIC

- AIC (Akaike Information Criterion) provides estimate of the risk in case of more general models. It has the form

$$L_J - |J|,$$

where

- L_J is a model log-likelihood
- $|J|$ is a number of model parameters
- AIC is equivalent to Mallows C_p in case of linear regression model with a Gaussian noise
- BIC (Bayesian Information Criterion) is equal to

$$L_J - |J| \log m$$

LOO CV

- Another possibility to estimate risk: leave-one-out cross-validation

$$\hat{R}_{CV}(J) = \frac{1}{m} \sum_{i=1}^m (y_i - \hat{y}_{(-i)})^2,$$

where $\hat{y}_{(-i)}$ is a prediction, obtained by a model, constructed using a sample $S_m \setminus \{(\mathbf{x}_i, y_i)\}$

- Increase computational efficiency using formula

$$\hat{R}_{CV}(J) = \frac{1}{m} \sum_{i=1}^m \left(\frac{y_i - \hat{y}_i(J)}{1 - U_{ii}(J)} \right)^2$$

$$U(J) = \mathbf{X}_J (\mathbf{X}_J^T \mathbf{X}_J)^{-1} \mathbf{X}_J^T$$

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LEARNING GUARANTEES

- Upper bound on a probability of over-training, valid for any sample S_m , rather general hypothesis class H and learner \mathcal{L} :

$$\mathbb{P}\left(\hat{R}(h; S^t) - \hat{R}(h; S_m) \geq \varepsilon\right) \leq \delta(\varepsilon, H), \quad h(\cdot) = \mathcal{L}(S_m)$$

- Then for any S_m , H and \mathcal{L} , and $\delta \in (0, 1)$ with a probability not less than $(1 - \delta)$ we get that

$$\hat{R}(h; S^t) \leq \hat{R}(h; S_m) + \varepsilon(\delta, H)$$

- Corrected Empirical Risk

$$\hat{R}(h; S_m) + \varepsilon(\delta, H) \rightarrow \min_{h, H}$$

REGULARIZATION

- Regularization penalizes complex models H

$$\hat{R}_{\text{pen}}(h; S_m) = \hat{R}(h; S_m) + \text{pen}(H)$$

- Let us consider linear models $H = \{h(\mathbf{x}) = \text{sign}(\mathbf{w}^T \cdot \mathbf{x})\}$ (classification) or $H = \{h(\mathbf{x}) = (\mathbf{w}^T \cdot \mathbf{x})\}$ (regression)
- Then
 - A) L_2 -regularization $\text{pen}(H) = \lambda \sum_{j=1}^N w_j^2$
 - B) L_1 -regularization $\text{pen}(H) = \lambda \sum_{j=1}^N |w_j|$
 - C) L_0 -regularization $\text{pen}(H) = \lambda \sum_{j=1}^N 1_{w_j \neq 0}$
- AIC & BIC are special cases of L_0 -regularization

BAYESIAN INTERPRETATION OF REGULARIZATION

- We consider linear regression model with a Gaussian i.i.d. noise
- Log-likelihood of S_m has the form

$$l(\mathbf{w}) = m \log \frac{1}{\sqrt{2\pi}\sigma} - \frac{1}{2\sigma^2} \sum_{i=1}^m (y_i - \mathbf{w}^T \mathbf{x}_i)^2$$

- Let us assume that

$$\mathbf{w} \sim \mathcal{N}(0, \tau^2 \mathbb{I})$$

- Posterior distribution of \mathbf{w} has the form

$$\begin{aligned} p(\mathbf{w} | S_m) &\propto p(S_m | \mathbf{w}) p(\mathbf{w}) \\ &= C \cdot \exp \left\{ -\frac{1}{2\sigma^2} \sum_{i=1}^m (y_i - \mathbf{w}^T \mathbf{x}_i)^2 \right\} \exp \left\{ -\frac{\mathbf{w}^T \mathbf{w}}{2\tau^2} \right\} \end{aligned}$$

BAYESIAN INTERPRETATION OF REGULARIZATION

- Log-posterior

$$\begin{aligned}l_{MAP}(\mathbf{w}|S_m) &= -\frac{1}{2\sigma^2} \sum_{i=1}^m (y_i - \mathbf{w}^T \mathbf{x}_i)^2 - \frac{1}{2\tau^2} \sum_{k=1}^N w_k^2 \\&= -\frac{m}{2\sigma^2} \left(\frac{1}{m} \sum_{i=1}^m (y_i - \mathbf{w}^T \mathbf{x}_i)^2 + \frac{\sigma^2}{m\tau^2} \sum_{k=1}^N w_k^2 \right) \\&= -\frac{m}{2\sigma^2} \left(\hat{R}(h; S_m) + \lambda \|\mathbf{w}\|^2 \right), \quad \lambda = \frac{\sigma^2}{m\tau^2}\end{aligned}$$

- Thus MAP estimate is the same as L_2 -regularized estimate

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FEATURE SELECTION

Why Feature Selection?

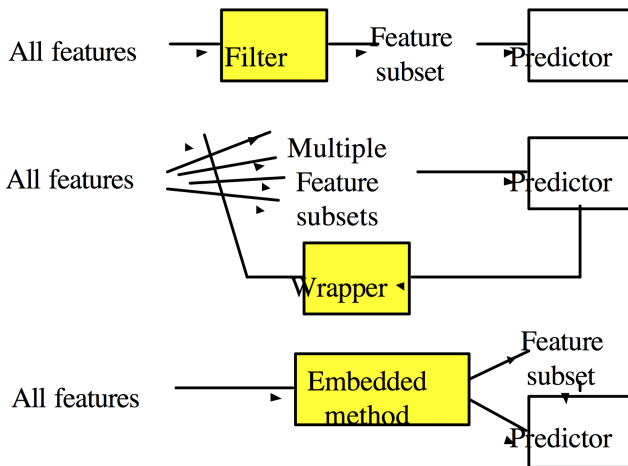
- Some algorithms scale (computationally) poorly with increased dimension
- Irrelevant features can confuse some algorithms
- Redundant features adversely affect regularization
- Removal of features can increase (relative) margin (and generalization)
- Reduces data set and resulting model size
- Note: Feature Selection is different from Feature Extraction
 - The latter transforms original features to get a small set of new features
 - Dimensionality Reduction is a type of Feature Extraction

FEATURE SELECTION METHODS

- Methods agnostic to the learning algorithm
 - Preprocessing based methods
 - A) E.g., remove a binary feature if it's ON in very few or most examples
 - Filter Feature Selection methods
 - A) Use some ranking criteria to rank features
 - B) Select the top ranking features
 - Wrapper Methods (keep the learning algorithm in the loop)
 - A) Requires repeated runs of the learning algorithm with different set of features
 - B) Can be computationally expensive

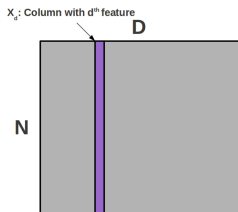
SCHEME OF FEATURE SELECTION METHODS

Filters, Wrappers, and Embedded methods



FILTER FEATURE SELECTION

- Uses heuristics but is much faster than wrapper methods



- Correlation Criteria: Rank features in order of their correlation with the labels

$$r(x_d, y) = \frac{\text{cov}(x_d, y)}{\sqrt{\text{var}(x_d)\text{var}(y)}}$$

- Mutual Information Criteria:

$$MI(x_d, y) = \sum_{x_d} \sum_y p(x_d, y) \log \frac{p(x_d, y)}{p(x_d)p(y)}$$

WRAPPER METHODS

Two types: Forward Search and Backward Search

- Forward Search
 - Start with no features
 - Greedily include the most relevant feature and estimate model's error on a renewed feature set
 - Stop when selected the desired number of features
- Backward Search
 - Start with all the features
 - Greedily remove the least relevant and estimate model's error on a renewed feature set
 - Stop when selected the desired number of features
- Inclusion/Removal criteria uses cross-validation